Supplementary Information

Size-induced brittle-to-ductile deformation of GaN pillars under room temperature compression

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Supplementary Video Captions

Supplementary video 1 *in situ* SEM compression test of a pillar with diameter of ~1.2μm (100× accelerated)

Supplementary video 2 *in situ* SEM compression test of a pillar with diameter of ~700nm (100× accelerated)

Supplementary video 3 *in situ* SEM compression test of a pillar with diameter of ~500nm (100× accelerated)

Supplementary video 4 *in situ* TEM compression test of a pillar with diameter of ~220nm (100× accelerated)